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PATENT  
81790.0214  
(Former Docket No. 005702-20068)

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MAR 15 2002

TC 2800 MAIL ROOM

In re application of:

Tomomi MOMOHARA

Serial No: 09/511,620

Filed: February 23, 2000

For: SEMICONDUCTOR INTEGRATED  
CIRCUIT DEVICE AND METHOD OF  
TESTING THE SAME

Art Unit: 2815

Examiner: J. Fenty

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11/1/01

Name

Date

*Kimberly Yee*  
Signature

**RESPONSE TO RESTRICTION REQUIREMENT  
AND AMENDMENT**

Box Non-Fee Amendment  
Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

In response to the Restriction Requirement dated October 2, 2001, Applicants, without  
traverse, elects for prosecution the claims of Group I, claims 5-8 and 20-40. Furthermore, please  
amend the above-referenced application as follows:

**IN THE SPECIFICATION:**

Starting on page 2, line 23, and continuing through page 9, line 23, delete the section of  
the specification entitled BRIEF SUMMARY OF THE INVENTION, and replace such deleted  
section with the following replacement section:

**"BRIEF SUMMARY OF THE INVENTION"**

B  
A semiconductor device according to an aspect of the present invention comprises: a  
semiconductor substrate of a first conductivity type; at least one first well of a second  
conductivity type formed in the semiconductor substrate; and at least one second well of the first  
conductivity type formed in at least one first well, wherein the semiconductor device is  
composed of semiconductor circuits each formed in at least one first well and at least one second  
well."